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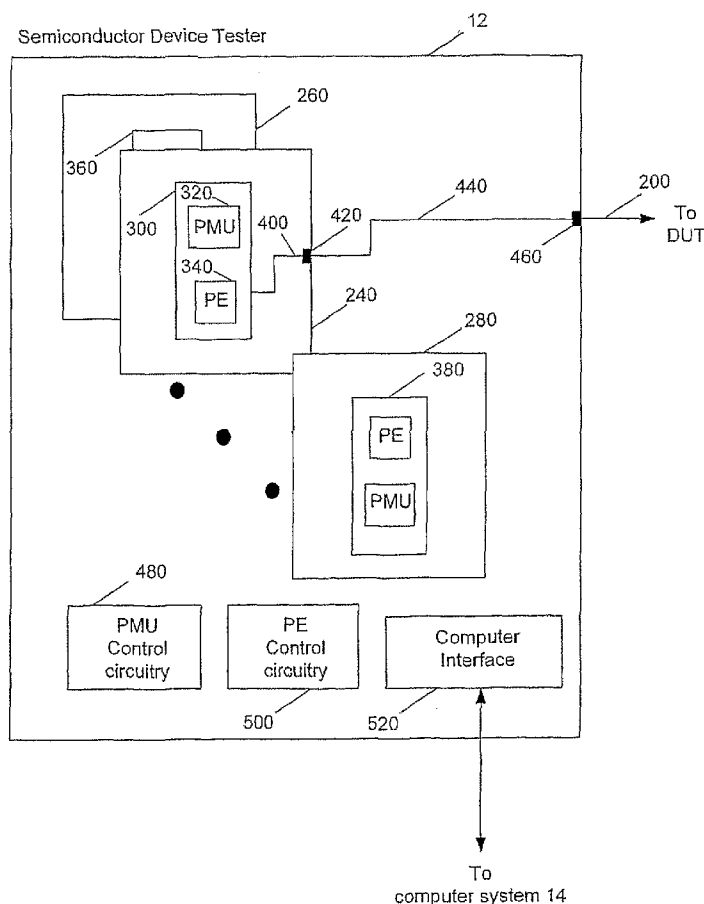
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(54) Title: USING A PARAMETRIC MEASUREMENT UNIT FOR CONVERTER TESTING



(57) Abstract: In one aspect, the invention is an integrated circuit (IC) for use in testing an analog-to-digital (ADC) converter includes a first channel of a parametric measurement unit (PMU) configured to send a force signal to the ADC. The IC also includes a first digital-to-analog converter (DAC) connected to the first channel of the PMU. The DAC has a DC level of accuracy of less than 1 millivolt. In another aspect, the invention is an integrated circuit (IC) for use in testing a digital-to-analog-converter-device-under-test (DACDUT). The IC includes a first channel of a parametric measurement unit (PMU) configured to send a force signal to the DACDUT and including an output port for taking measurements, a first digital-to-analog converter (DAC) connected to the first channel of the PMU and a PMU measurement path connected to the output port having a DC level of accuracy of less than 1 mV.

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